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This is to certify that your manuscript Title "**DETERMINATION OF INTRINSIC STRESS DUE TO LEAD SELENIDE THIN FILMS USING DOUBLE EXPOSURE HOLOGRAPHIC INTERFEROMETRY**" has been reviewed and based on reviewer's comments it is Published in May 2017 issue titled authored by **Mane R.D., Chikode P.P. and Dongare M.B.**. This Journal is Double Blind Peer Reviewed and Refereed Journal and follows process guided by UGC, New Delhi.

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